## Applicant(s)/Patent Under Reexamination OKAWA ET AL. Examiner Mark Ruthkosky Applicant(s)/Patent Under Reexamination OKAWA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5910382	06-1999	Goodenough	429/218.1
	В	US-5871866	02-1999	Barker	429/231.1
	С	US- /			
	۵	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ŀ	US-			
	j	US-			
	К	US-			
	L	ys-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 63-125188	11-1989	JPO	Takayuki	H01M 10/40
	0					
	Р					
	Q	/				
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

\* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

U

V

X

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.